



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AO4430**  
*30V N-Channel MOSFET*

### General Description

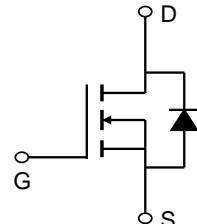
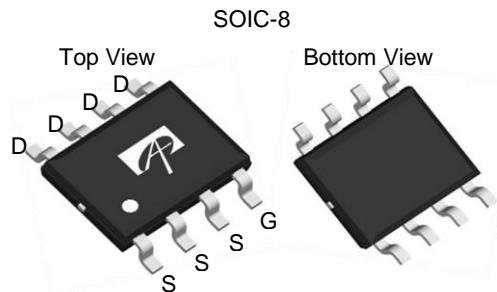
The AO4430 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , shoot-through immunity, body diode characteristics and ultra-low gate resistance. This device is ideally suited for use as a low side switch in Notebook CPU core power conversion.

RoHS and Halogen-Free Compliant

### Product Summary

$V_{DS}$  (V) = 30V  
 $I_D$  = 18A ( $V_{GS}$  = 10V)  
 $R_{DS(ON)} < 5.5\text{m}\Omega$  ( $V_{GS}$  = 10V)  
 $R_{DS(ON)} < 7.5\text{m}\Omega$  ( $V_{GS}$  = 4.5V)

100% UIS Tested  
100%  $R_g$  Tested



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>A</sup> F	$I_D$	18	A
$T_A=70^\circ\text{C}$		15	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	80	
Power Dissipation	$P_D$	3	W
$T_A=70^\circ\text{C}$		2.1	
Avalanche Current <sup>B</sup>	$I_{AR}$	30	A
Repetitive avalanche energy 0.3mH <sup>B</sup>	$E_{AR}$	135	mJ
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	31	40	°C/W
Steady-State		59	75	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	16	24	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 20\text{V}$			100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	1.8	2.5	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	80			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=18\text{A}$ $T_J=125^\circ\text{C}$		4.7	5.5	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=15\text{A}$		6.5	8	
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=18\text{A}$		82		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
$I_s$	Maximum Body-Diode Continuous Current				4.5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$	4660	6060	7270	pF
$C_{\text{oss}}$	Output Capacitance		425	638	960	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance		240	355	530	pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.2	0.45	0.9	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=18\text{A}$	80	103	124	nC
$Q_g(4.5\text{V})$	Total Gate Charge		37	48	58	nC
$Q_{\text{gs}}$	Gate Source Charge			18		nC
$Q_{\text{gd}}$	Gate Drain Charge			15		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=0.83\Omega, R_{\text{GEN}}=3\Omega$		12	16	ns
$t_r$	Turn-On Rise Time			8	12	ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			51.5	70	ns
$t_f$	Turn-Off Fall Time			8.8	14	ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=18\text{A}, dI/dt=100\text{A}/\mu\text{s}$		33.5	44	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=18\text{A}, dI/dt=100\text{A}/\mu\text{s}$		22	30	nC

A: The value of  $R_{\text{QA}}$  is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\text{QA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{JL}}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.

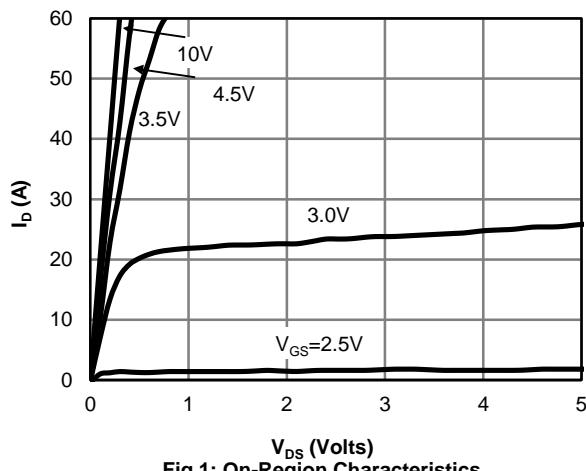
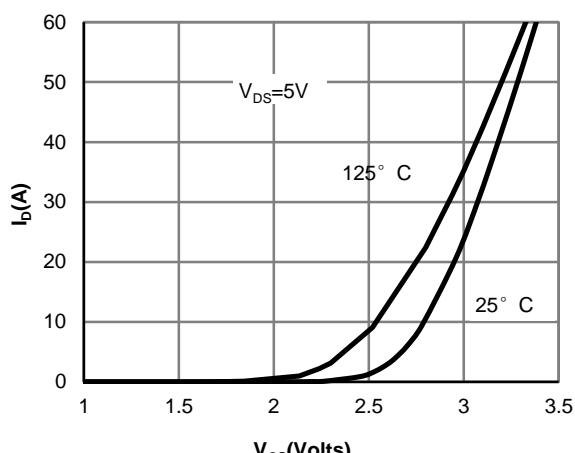
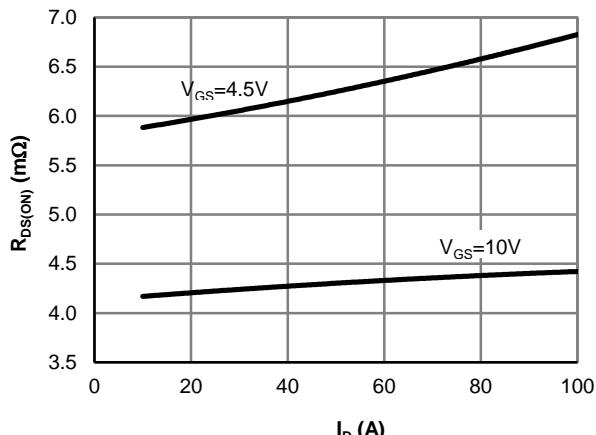
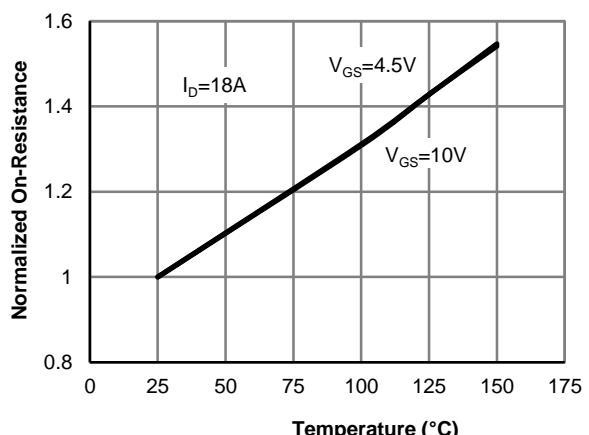
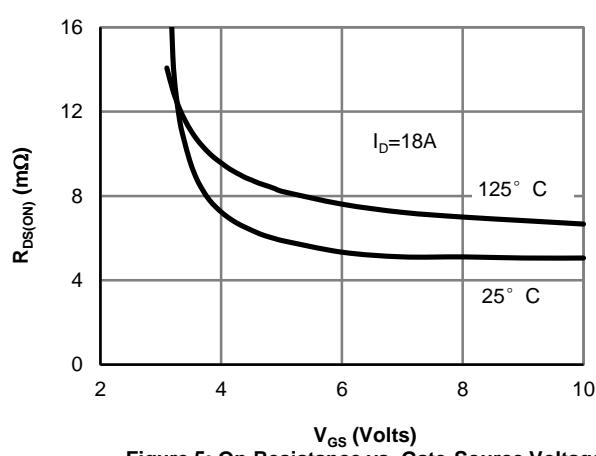
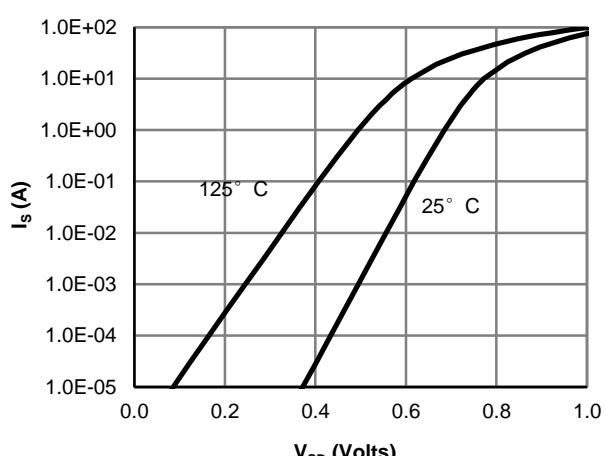
E. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

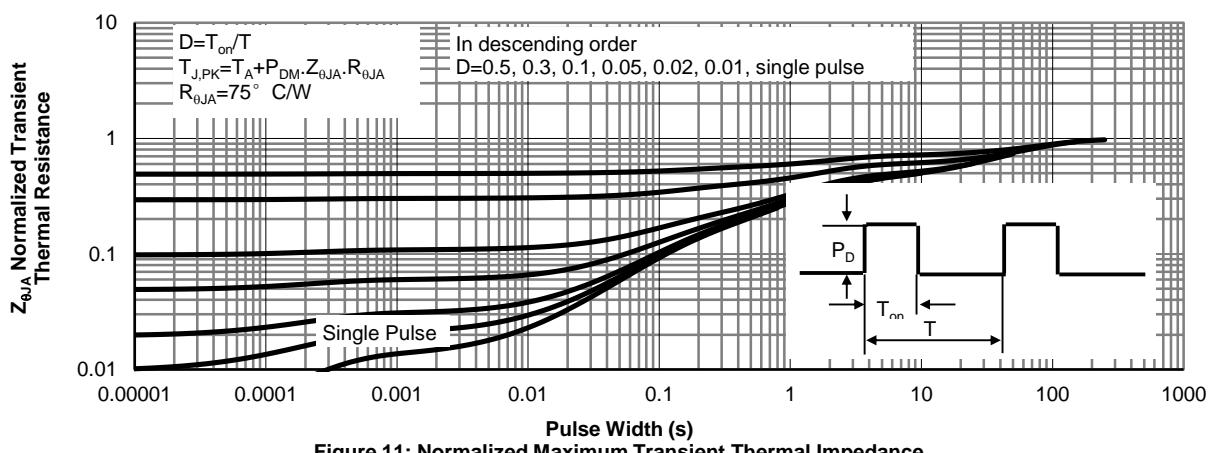
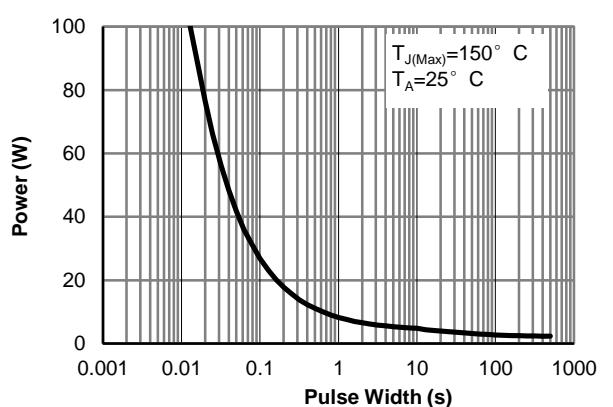
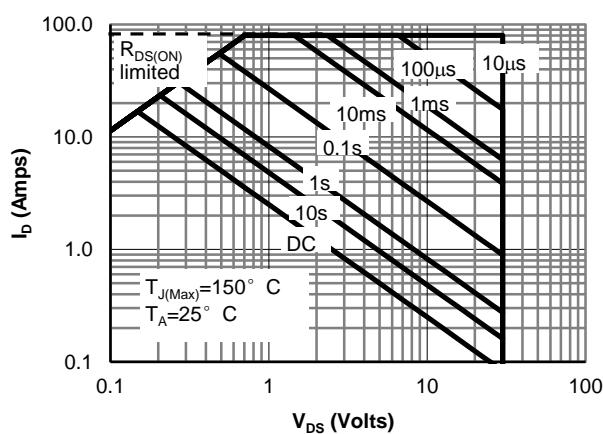
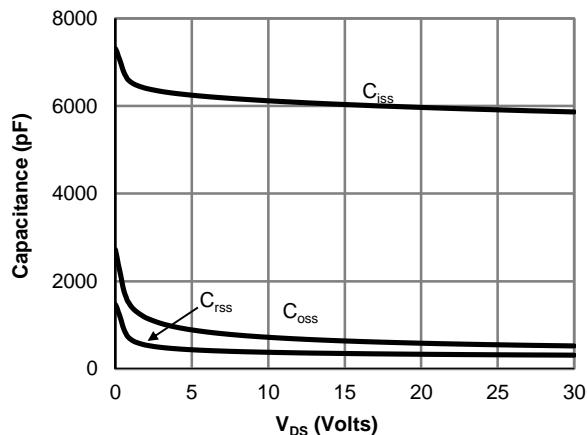
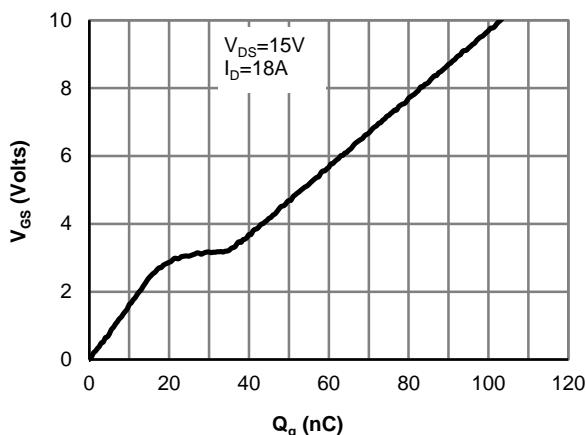
F. The current rating is based on the  $t \leq 10\text{s}$  junction to ambient thermal resistance rating.

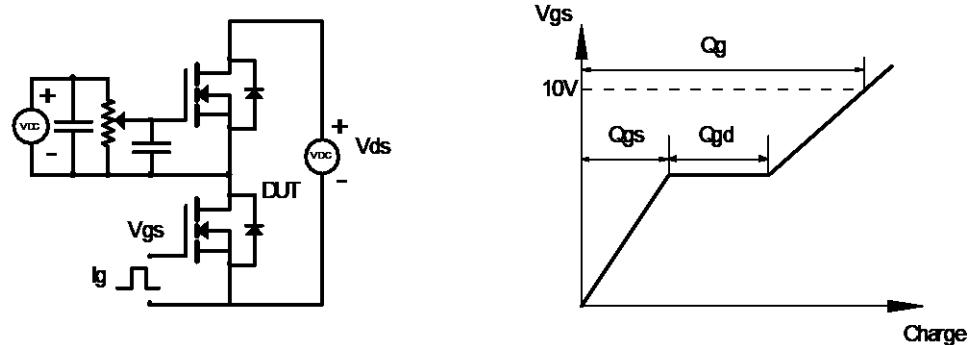
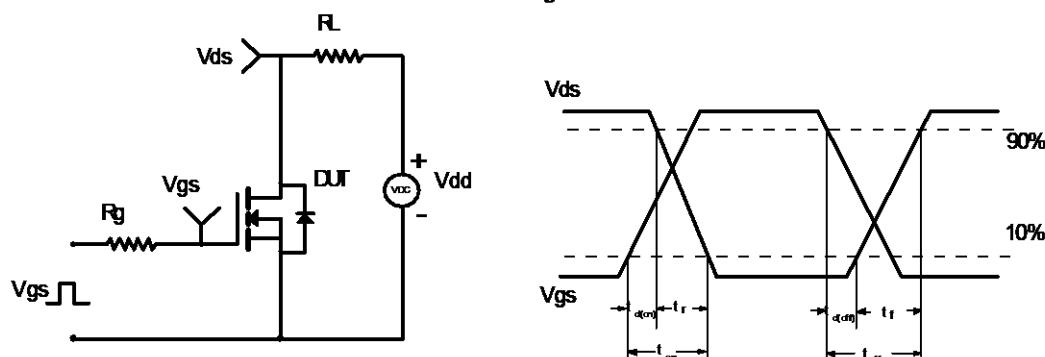
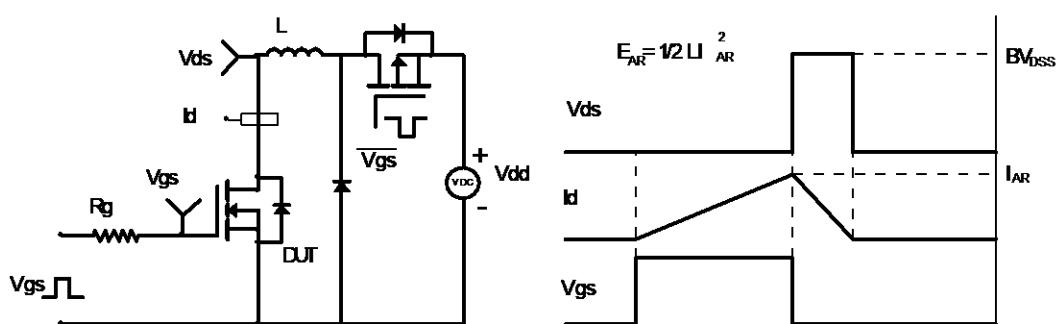
APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO MAKE CHANGES TO PRODUCT SPECIFICATIONS WITHOUT NOTICE. IT IS THE RESPONSIBILITY OF THE CUSTOMER TO EVALUATE SUITABILITY OF THE PRODUCT FOR THEIR INTENDED APPLICATION. CUSTOMER SHALL COMPLY WITH APPLICABLE LEGAL REQUIREMENTS, INCLUDING ALL APPLICABLE EXPORT CONTROL RULES, REGULATIONS AND LIMITATIONS.

AOS' products are provided subject to AOS' terms and conditions of sale which are set forth at:

[http://www.aosmd.com/terms\\_and\\_conditions\\_of\\_sale](http://www.aosmd.com/terms_and_conditions_of_sale)

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Fig 1: On-Region Characteristics**

**Figure 2: Transfer Characteristics**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**

**Figure 4: On-Resistance vs. Junction Temperature**

**Figure 5: On-Resistance vs. Gate-Source Voltage**

**Figure 6: Body-Diode Characteristics**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
